BLF6G10-160RN; **BLF6G10LS-160RN**

Power LDMOS transistor

Rev. 02 — 21 January 2010

Product data sheet

1. Product profile

1.1 General description

160 W LDMOS power transistor for base station applications at frequencies from 700 MHz to 1000 MHz.

Table 1. Typical performance

Typical RF performance at $T_{\text{case}} = 25 \, ^{\circ}\text{C}$ in a class-AB production test circuit.

Mode of operation	f	V _{DS}	P _{L(AV)}	Gp	η _D	ACPR
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	920 to 960	32	32	22.5	27	-41 <mark>[1]</mark>

^[1] Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7.5 dB at 0.01 % probability on CCDF per carrier; carrier spacing 5 MHz.

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

1.2 Features

- Typical 2-carrier W-CDMA performance at frequencies of 920 MHz and 960 MHz, a supply voltage of 32 V and an I_{Dq} of 1200 mA:
 - Average output power = 32 W
 - ◆ Power gain = 22.5 dB
 - ◆ Efficiency = 27 %
 - ◆ ACPR = -41 dBc
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (700 MHz to 1000 MHz)
- Internally matched for ease of use
- Compliant to Directive 2002/95/EC, regarding restriction of hazardous substances (RoHS)



1.3 Applications

■ RF power amplifiers for GSM, GSM EDGE, W-CDMA and CDMA base stations and multi carrier applications in the 700 MHz to 1000 MHz frequency range.

2. Pinning information

Table 2. Pinning

-160RN (SOT502A)			
drain			
gate			, ∟¹
source	<u>[1]</u>		2 —
			3 sym112
LS-160RN (SOT502B)			
drain			
gate			<u>, </u>
source	<u>[1]</u>	2	2 —
			- • 3 sym112
	source S-160RN (SOT502B) drain gate	source [1] LS-160RN (SOT502B) drain gate	source [1] 2 Source [1] 2 Source [1] 3

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Packag	ackage					
	Name	Description	Version				
BLF6G10-160RN	-	flanged LDMOST ceramic package; 2 mounting holes; 2 leads	SOT502A				
BLF6G10LS-160RN	-	earless flanged LDMOST ceramic package; 2 leads	SOT502B				

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
I_D	drain current		-	39	Α
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		-	225	°C

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Туре	Тур	Unit
$R_{\text{th(j-case)}}$	thermal resistance from	$T_{case} = 80 ^{\circ}C;$	BLF6G10-160RN	0.5	K/W
	junction to case	$P_L = 32 W$	BLF6G10LS-160RN	0.44	K/W

6. Characteristics

Table 6. Characteristics

 $T_i = 25$ °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.72 \text{ mA}$	65	-	-	V
V _{GS(th)}	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 216 \text{ mA}$	1.4	1.9	2.4	V
V_{GSq}	gate-source quiescent voltage	$V_{DS} = 32 \text{ V};$ $I_D = 1300 \text{ mA}$	1.7	2.2	2.7	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 32 \text{ V}$	-	-	5	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	30.6	39	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 13 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	450	nΑ
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 7.5 \text{ A}$	-	13.5	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 7.5 \text{ A}$	-	0.07	-	Ω
C _{rs}	feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 32 \text{ V};$ f = 1 MHz	-	4.2	-	pF

7. Application information

Table 7. Application information

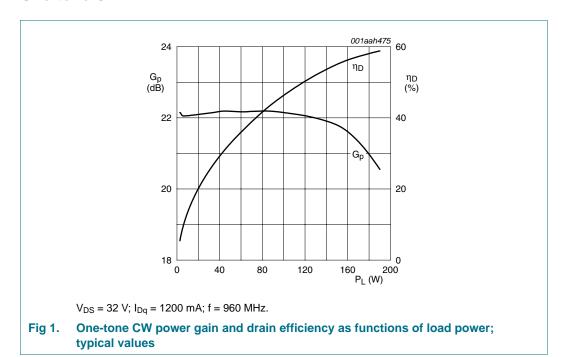
Mode of operation: 2-carrier W-CDMA; PAR 7.5 dB at 0.01 % probability on CCDF; 3GPP test model 1; 1-64 PDPCH; f_1 = 922.5 MHz; f_2 = 927.5 MHz; f_3 = 952.5 MHz; f_4 = 957.5 MHz; RF performance at V_{DS} = 32 V; I_{Dq} = 1200 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	32	-	W
G_p	power gain	$P_{L(AV)} = 32 \text{ W}$	21	22.5	-	dB
RL_{in}	input return loss	$P_{L(AV)} = 32 \text{ W}$	-	-8	-5.5	dB
η_{D}	drain efficiency	$P_{L(AV)} = 32 \text{ W}$	25	27	-	%
ACPR	adjacent channel power ratio	$P_{L(AV)} = 32 \text{ W}$	-	-41	-38	dBc

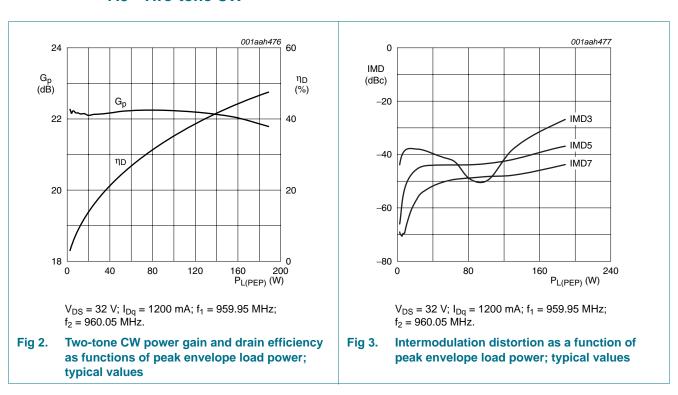
7.1 Ruggedness in class-AB operation

The BLF6G10-160RN and BLF6G10LS-160RN are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 32 V; I_{Dq} = 1200 mA; P_{L} = 160 W (CW); f = 960 MHz.

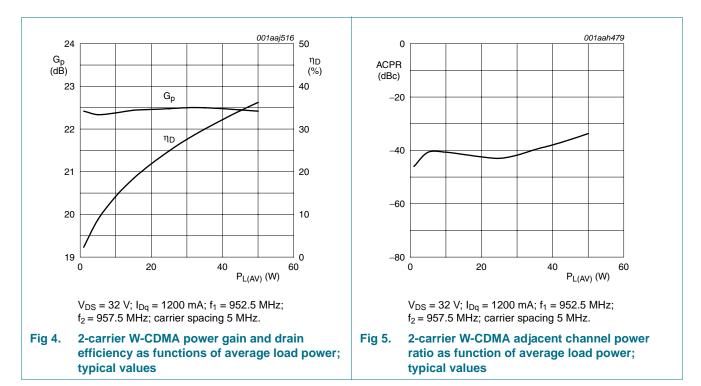
7.2 One-tone CW



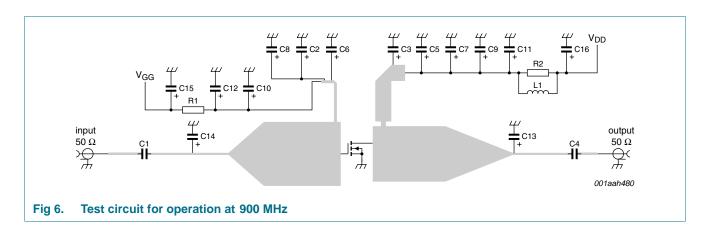
7.3 Two-tone CW



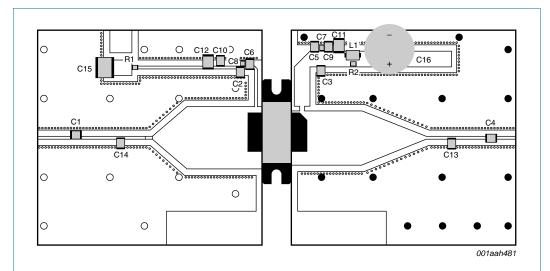
7.4 2-carrier W-CDMA



8. Test information



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The striplines are on a double copper-clad Taconic RF35 Printed-Circuit Board (PCB) with ϵ_{r} = 3.5 and thickness = 0.76 mm.

See Table 8 for list of components.

Fig 7. Component layout

Table 8. List of components (see Figure 6 and Figure 7)

All capacitors should be soldered vertically.

Component	Description	Value	Remarks
C1, C2, C3, C4	multilayer ceramic chip capacitor	68 pF	П
C5, C6	multilayer ceramic chip capacitor	560 pF	П
C7, C8	multilayer ceramic chip capacitor	330 nF; 50 V	[2]
C9, C10	multilayer ceramic chip capacitor	1.5 μF; 50 V	[2]
C11, C12	multilayer ceramic chip capacitor	4.5 μF; 50 V	[2]
C13	multilayer ceramic chip capacitor	2.20 pF	[1]
C14	multilayer ceramic chip capacitor	2.7 pF	[1]
C15	SMD tantalum capacitor	47 μF; 20 V	
C16	electrolytic capacitor	220 μF	
L1	ferrite SMD bead	-	Ferroxcube BDS 3/3/8.9-4S2 or equivalent
R1	SMD resistor	4.7 Ω; 0.1 W	
R2	SMD resistor	6.8 Ω; 0.1 W	

^[1] American Technical Ceramics type 100B or capacitor of same quality.

[2] TDK or capacitor of same quality.

9. Package outline

Flanged LDMOST ceramic package; 2 mounting holes; 2 leads

SOT502A

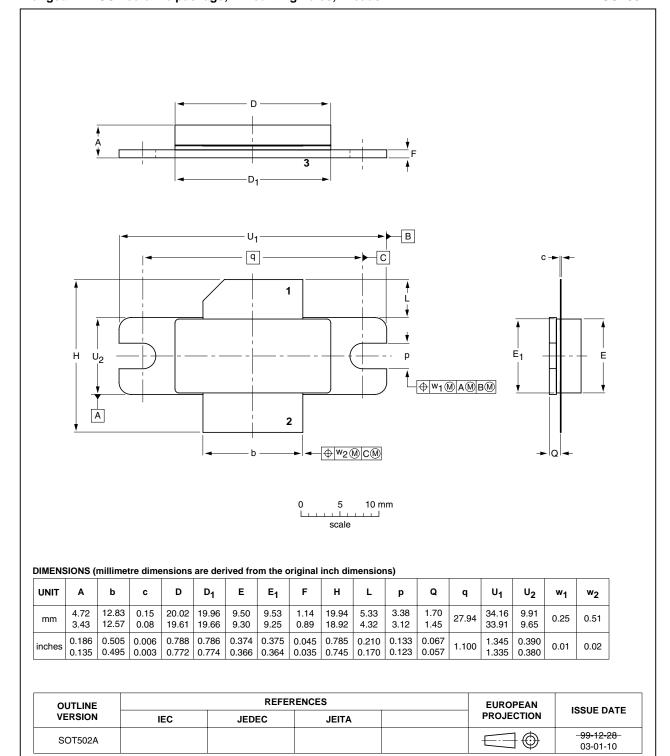


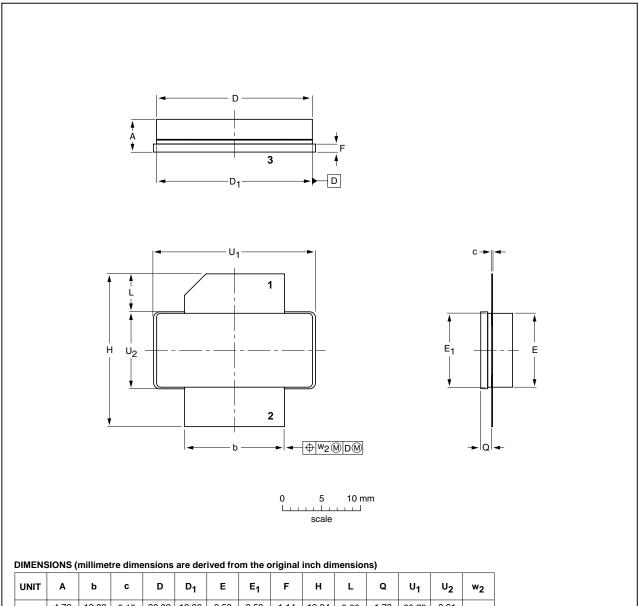
Fig 8. Package outline SOT502A

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Earless flanged LDMOST ceramic package; 2 leads

SOT502B



	JNIT	Α	b	С	D	D ₁	E	E ₁	F	Н	L	Q	U ₁	U ₂	w ₂
	mm	4.72 3.43	12.83 12.57	0.08	20.02 19.61	19.66	9.30	9.53 9.25	1.14 0.89	19.94 18.92	5.33 4.32		20.70 20.45	9.65	0.25
i	nches	0.186 0.135	0.505 0.495	0.006 0.003	0.788 0.772	0.786 0.774	0.374 0.366	0.375 0.364	0.045 0.035	0.785 0.745	0.210 0.170	0.067 0.057	0.815 0.805	0.390 0.380	0.010

OUTLINE		REFER	ENCES		EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT502B						03-01-10- 07-05-09	

Fig 9. Package outline SOT502B

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10. Abbreviations

Table 9. Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CDMA	Code Division Multiple Access
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
EDGE	Enhanced Data rates for GSM Evolution
GSM	Global System for Mobile communications
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
PAR	Peak-to-Average power Ratio
PDPCH	transmission Power of the Dedicated Physical CHannel
RF	Radio Frequency
SMD	Surface Mounted Device
VSWR	Voltage Standing-Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF6G10-160RN_10LS-160RN_2	20100121	Product data sheet	-	BLF6G10-160RN_10LS-160RN_1
Modifications:	• Section 1 from 800		on" lower frequen	cy range extended to 700 MHz
	 Section 1 	.2 "Features" lower fr	equency range e	xtended to 700 MHz from 800 MHz.
	 <u>Section 1</u> 800 MHz. 		er frequency rang	e extended to 700 MHz from
	 Section 1: 	2 "Legal information"	export control dis	sclaimer added.
BLF6G10-160RN_10LS-160RN_1	20090120	Product data sheet	-	-

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BLF6G10(LS)-160RN

Power LDMOS transistor

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